

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB TEST CERTIFICATE

Product

Accelerated Surface Area and Porosimetry System

Name and address of the applicant

Micromeritics Instrument Corporation
4356 Communications Drive
Norcross, GA, 30093
United States of America

Name and address of the manufacturer

Micromeritics Instrument Corporation
4356 Communications Drive
Norcross, GA, 30093
United States of America

Name and address of the factory

Note: When more than one factory, please report on page 2

Micromeritics Instrument Corporation
4356 Communications Drive
Norcross, GA, 30093
United States of America

 Additional information on page 2

Ratings and principal characteristics

100-240Vac, 50-60Hz, 4A

Trademark / Brand (if any)



micromeritics

Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

ASAP 2460

Additional information (if necessary may also be reported on page 2)

 Additional information on page 2

A sample of the product was tested and found to be in conformity with

IEC 61010-1:2010/AMD1:2016, IEC 61010-2-081:2019

Comments:

Refer to the Test Report for the Summary of Compliance with National Deviations

As shown in the Test Report Ref. No. which forms part of this Certificate

105453786ATL-001C, 105453786ATL-001D

This CB Test Certificate is issued by the National Certification Body

Intertek Testing Services NA, Inc.
545 E. Algonquin Road, Arlington Heights
IL 60005
United States of America

Date: 2023-12-14

Signature: Matt Snyder